## Applicant(s)/Patent Under Application/Control No. Reexamination 10/517,887 ORTT ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 David W. Scheuermann 2834 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В С US- . D US-US-Ε F US-G US-Н US-US-١ US-J Κ US-US-L М US-FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY 06-1994 NAKAZAWA, HIRONOBU JP 06155268 A Japan Ν 0 Р Q R s T

## **NON-PATENT DOCUMENTS**

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